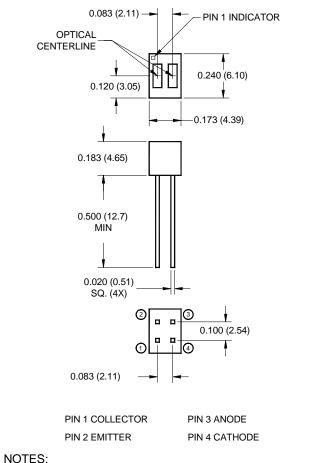


QRD1113/1114 REFLECTIVE OBJECT SENSOR

PACKAGE DIMENSIONS



1. Dimensions for all drawings are in inches (millimeters).

3. Pins 2 and 4 typically .050" shorter than pins 1 and 3.

4. Dimensions controlled at housing surface.

unless otherwise specified.

2. Tolerance of \pm .010 (.25) on all non-nominal dimensions

RMA flux is recommended. Methanol or isopropyl alcohols are recommended as cleaning agents.

4. Soldering iron 1/16" (1.6mm) from housing.

FEATURES

Phototransistor Output

Compact Package

• Daylight filter on sensor

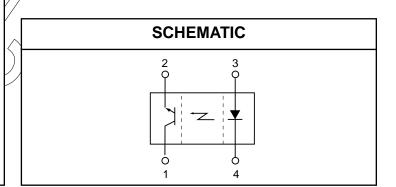
No contact surface sensing

· Unfocused for sensing diffused surfaces

- 5. As long as leads are not under any spring tension.
- 6. D is the distance from the sensor face to the reflective surface.

NOTES (Applies to Max Ratings and Characteristics Tables.) 1. Derate power dissipation linearly 1.33 mW/°C above 25°C.

- 7. Cross talk (I_{CX}) is the collector current measured with the indicator current on the input diode and with no reflective surface.
- 8. Measured using an Eastman Kodak neutral white test card with 90% diffused reflecting as a reflective surface.



ABSOLUTE MAXIMUM RATINGS (T _A = 25°C unless otherwise specified)						
Parameter	Symbol	Rating	Units			
Operating Temperature	T _{OPR}	-40 to +85	°C			
Storage Temperature	T _{STG}	-40 to +85	٦°			
Lead Temperature (Solder Iron) ^(2,3)	T _{SOL-I}	240 for 5 sec	°C			
Lead Temperature (Solder Flow) ^(2,3)	T _{SOL-F}	260 for 10 sec	٦°			
EMITTER						
Continuous Forward Current	١ _F	50	mA			
Reverse Voltage	V _R	5	V			
Power Dissipation ⁽¹⁾	PD	100	mW			
SENSOR						
Collector-Emitter Voltage	V _{CEO}	30	V			
Emitter-Collector Voltage	V _{ECO}		V			
Power Dissipation(1)	PD	100	mW			

FAIRCHILD

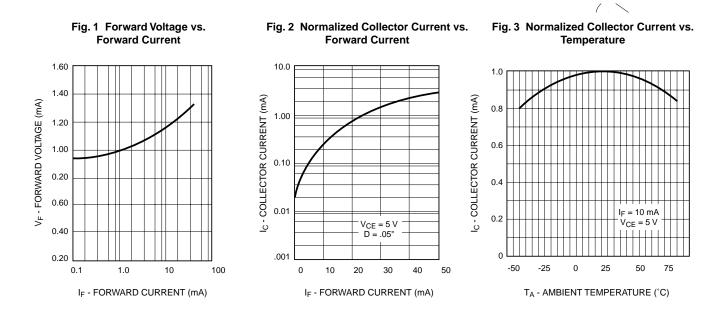
QRD1113/1114 REFLECTIVE OBJECT SENSOR

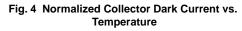
PARAMETER	TEST CONDITIONS	SYMBOL	MIN	TYP	MAX	UNITS
EMITTER	I _F = 20 mA	V _F	_	_	1.7	V
Forward Voltage	F = 20 mA					
Reverse Current	$V_R = 5 V$	I _R	_	_	100	μA
Peak Emission Wavelength	I _F = 20 mA	λ_{PE}	—	940	—	nm
SENSOR	$I_c = 1 \text{ mA}$	BV _{CEO}	30	_	_	V
Collector-Emitter Breakdown	$I_{\rm C} = 1$ IIIA					
Emitter-Collector Breakdown	I _E = 0.1 mA	BV _{ECO}	5	_	_	V
Dark Current	$V_{CE} = 10 \text{ V}, \text{ I}_{F} = 0 \text{ mA}$	I _D	_	_	100	nA
COUPLED	$I_{\rm F}$ = 20 mA, $V_{\rm CE}$ = 5 V	I _{C(ON)}	0.300	_		mA
QRD1113 Collector Current	D = .050" (6,8)	C(ON)				
QRD1114 Collector Current	$I_{\rm F}$ = 20 mA, $V_{\rm CE}$ = 5 V	I _{C(ON)}	1	_	_	mA
	D = .050" ^(6,8)					
Collector Emitter	IF = 40 mA, Ic = 100 µA		_	_	0.4	V
Saturation Voltage	D = .050" ^(6,8)	VCE (SAT)				
Cross Talk I _F	= 20 mA, V_{CE} = 5 V, EE = 0 ⁽⁷⁾	I _{CX}	_	.200	10	μA
Rise Time	V_{CE} = 5 V, R_L = 100 Ω	tr	_	10	_	μs
Fall Time	$I_{C(ON)} = 5 \text{ mA}$	t _f	_	50		μs



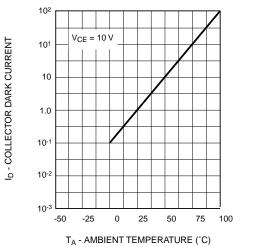
QRD1113/1114 REFLECTIVE OBJECT SENSOR

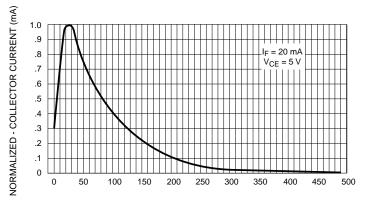
TYPICAL PERFORMANCE CURVES











REFLECTIVE SURFACE DISTANCE (mils)



QRD1113/1114 REFLECTIVE OBJECT SENSOR

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